

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Joachim STUMPE et al.

International Appln: PCT/EP2004/005911
Filed: June 1, 2003

U.S. Application No.: Not Yet Assigned

For: METHOD AND DEVICE FOR
THREE-DimensionALLY
DETERMINING THE REFRACTIVE
INDEX OF TRANSPARENT OR
PARTIALLY TRANSPARENT
LAYERS

Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

Confirmation No.: Not Yet Assigned

Atty. Docket No.: 31583-226294 RK

Customer No.: 26694

Information Disclosure Statement

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is an Information Disclosure Statement submitted under 37 C.F.R. § 1.97 within the time specified under 37 C.F.R. § 1.97(c).

In order to comply the duty of disclosure pursuant to 37 C.F.R. § 1.56, submitted herewith is a Form PTO/SB/08A listing the documents cited in the international application and in the International Search Report of International Application No. PCT/EP2004/005911. The relevance of each document is indicated therein.

Copies of the documents cited in the International Search Report are not being provided since copies are furnished directly by WIPO under an exchange program between the PTO, the EPO and the JPO.


If the copies of the documents cited in the International Search Report were not furnished and a copy of each cited document is desired, please inform the undersigned and a copy of the missing documents will be supplied.

Applicant(s): Joachim STUMPE et al.
Atty. Docket: 31583-226294 RK

In view of the above, no further statement of relevance need be given, and as all requirements of 37 C.F.R. § 1.97 and § 1.98, and all official guidelines pertaining to Information Disclosure Statements have been complied with, it is respectfully requested that the Examiner consider the cited publications and make them of record.

Respectfully submitted,

Date: December 5, 2005


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PTO/SB/08A (08-00)

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Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 2

Application Number NOT YET ASSIGNED
Filing Date Concurrently
First Named Inventor Joachim STUMPE et al.
Prior Group Art Unit Not Yet Assigned
Prior Examiner Name Not Yet Assigned
Attorney Docket Number 31583-226294 RK

IAPO Rec'd PCT/PTO 25 DEC 2005

U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
	AA	3,963,348		ITO et al.	6/15/1976	
	AB	5,526,118		MIYAGAWA et al.	6/11/1996	

FOREIGN PATENT DOCUMENTS

Examiner Initials *	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ₈
		Office No. ³	Number ⁴	Kind Code ⁵ (if known)				
	AC	WO	01/42769		PRIESTLEY	6/14/2001		
	AD	JP	11 037937		RICOH CO. LTD.	2/12/1999		
	AE	JP	03 195905		AISIN SEIKI CO. LTD.	8/27/1991		

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	NOT YET ASSIGNED
				Filing Date	Concurrently
				First Named Inventor	Joachim STUMPE et al.
				Group Art Unit	Not Yet Assigned
				Examiner Name	Not Yet Assigned
				Attorney Docket Number	31583-226294 RK
Sheet	2	of	2		

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	AF	RAMSDALE et al., "Ellipsometric Determination of Anisotropic Optical Constants In Electroluminescent Conjugated Polymers", Advanced Materials, VCH, Verlagsgesellschaft, Weinheim, DE, vol. 14, no. 3, 5 February 2002, pp. 212-215	
	AG	BORTCHAGOVSKY E.G., "Ellipsometric Method for Investigation of the Optical Anisotropy of Thin Films: Theory and Calculations", Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 307, No. 1-2, 10 October 1997, pages 192-199	
	AH	T. SRIKHIRINM, "An Investigation of the Photoinduced Changes of Absorption of High-Performance Photoaddressable Polymers", Chemphyschem, vol. 3, 2002, pp. 335-345	
	AI	BORTCHAGOVSKY E.G. et al., "Comparison of Ellipsometric Methods for Separate Determination of Thickness and Optical Constants of Thin Films", Folia Biolgoica, vol. 4517, 5 June 2000, pp. 126-133	
	AJ	JUNG C.C. et al., "Three Dimensional Anisotropies Induced by Light In Thin Polymer Films", Proc. Spei - Int. Soc. Opt. Eng. (USA), "Proceedings of The Spie - The International Society for Optical Engineering, 2003, Spie-Int. Soc. Opt. Eng. USA, vol. 5212, no. 1, 4 August 2003, pp. 83-93	
	AK	Patent Abstracts of Japan, vol. 1999, No. 05, 31 May 1999	
	AL	Patent Abstracts of Japan, vol. 015, No. 460, 21 November 1991	

Examiner Signature		Date Considered	
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